FEATURES

- Aries unique universal socketing system allows the socket to be easily configured for any package, on any pitch (or multiple pitch) from 0.2mm or greater, in any configuration, with little or no tooling charge or extra lead-time.
- For Test & Burn-In of CSP, µBGA, Bump-Array, QFN, QFP, MLF, DFN, SSOP, TSSOP, TSOP, SOP, SOIC, LGA, LCC, PLCC, TO and any SMT package style made. Also can be compatible with PGA packaged devices.
- Quick and easy Probe Replacement System: the complete set of probes can be removed and a new set (interposer) can be inserted quickly and easily. The old set can be returned to the factory for repair and sent back within one day.
- The Au over Ni-plated compression Spring-Probes leave very small witness marks on the bottom surface of the device solder balls.
- Standard molded socket format can accommodate any device package of 6.5mm or smaller, by using machined (for small quantities) or custom molded (for large quantities) pressure pads and interposers.
- Pressure pad compression spring provides proper force against device and allows for height variations in device thickness.
- 4-point crown insures scrub on solder balls, and raised tip probe provides scrub on pads.
- Signal path during test only 0.077 [1.96].

GENERAL SPECIFICATIONS

- 1dB BANDWIDTH: at 18.5GHz, <3dB to 39.7GHz (0.50mm pitch)
- PIN INDUCTANCE: 0.59nH (@ 0.50mm pitch)
- MUTUAL CAPACITANCE: 0.12pF
- VSWR: <2:1 to 38GHz
- CONTACT RESISTANCE: <40 mΩ
- COMPRESSION SPRING PROBES: heat-treated BeCu
- COMPRESSION SPRING PROBE PLATING: 30µ [0.75µ] min. Au per MIL-G-45204 over 30µ [0.75µ] min. Ni per SAE AMS-QQ-N-290
- ESTIMATED CONTACT LIFE: 500,000 cycles min.
- CONTACT FORCE: 6g per contact on 0.20-0.29mm pitch
  : 15g per contact on 0.30-0.35mm pitch
  : 16g per contact on 0.40-0.45mm pitch
  : 25g per contact on 0.50-0.75mm pitch
  : 25g per contact on 0.80mm pitch or larger
- MOLDED SOCKET COMPONENTS: UL 94V-0 Ultem

MOUNTING CONSIDERATIONS

- See “PCB FOOTPRINT TOP VIEW” for requirements
- REQUIRES: two #0-80 screws (supplied) and PEM nuts for mounting (not supplied). Mounting holes size shown may differ depending on PEM nut selected
- NOTE: Sockets must be handled with care when mounting or removing sockets to/from PCB to avoid damaging spring contacts.
- TEST PCB MINIMUM DIAMETER “G”: 0.025 [0.64] (large probe 0.80mm pitch and larger)
  : 0.015 [0.38] (small probe 0.50-0.75mm pitch)
  : 0.012 [0.31] (small probe 0.40-0.45mm pitch)
  : 0.009 [0.23] (small probe 0.30-0.35mm pitch)
  : 0.004 [0.10] (small probe 0.20-0.20mm pitch)
- TEST PCB DIAMETER SPRING PROBE PAD PLATING: 30µ [0.75µ] min. Au per MIL-G-45204 over 30µ [0.75µ] min. Ni per SAE AMS-QQ-N-290. Pad must be the same height as top surface of PCB. Please refer to the Custom Socket Drawing supplied by Aries after receipt of your order for your specific application.

ORDERING INFORMATION

Consult Factory

CLEANING, HANDLING, MOUNTING & PROBE REPLACEMENT INFO

A detailed device drawing must be sent to Aries to quote and design a socket.

See Data Sheet for...

- CSP Sockets
  - 23016 Hybrid Socket
  - 23021 µBGA up to 6.5mm
  - 23017 µBGA up to 13mm
  - 23018 µBGA up to 27mm
  - 23018-APP w/Adj Pressure Pad
  - 23019 µBGA up to 40mm
  - 23020 µBGA up to 55mm
  - 23023 Optical Failure Analysis
- RF Sockets
  - 24008 RF up to 13mm
  - 24009 RF up to 27mm
  - 24009-APP w/Adj Pressure Pad
  - 24011 RF up to 40mm
  - 24012 RF up to 55mm
  - 24010 RF Machined Socket
  - 23022 Kelvin Test Socket
High-Frequency Center Probe Test Socket
for Devices up to 6.5mm Square

ALL DIMENSIONS: INCHES [MILLI-METERS]
ALL TOLERANCES: ±0.005 [0.13] UNLESS OTHERWISE SPECIFIED

CUSTOMIZATION: In addition to the standard products shown on this page, Aries specializes in custom design and production. Special materials, platings, sizes, and configurations can be furnished, depending on the quantity. NOTE: Aries reserves the right to change product general specifications without notice.

FULL-ARRAY SHOWN AS AN EXAMPLE; YOUR SPECIFIC DEVICE PATTERN/FOOTPRINT WILL BE SUPPLIED WHEN ORDERED.